Notice of References Cited 10/718,699 Reexamination INABA ET AL. Examiner Jacques Veillard Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,883,001	04-2005	Abe, Seiichiro	707/10
*	В	US-6,701,318	03-2004	Fox et al.	707/10
*	C	US-6,473,754	10-2002	Matsubayashi et al.	707/5
*	D	US-7,035,861	04-2006	Kayahara, Naoki	707/100
*	E	US-7,120,625	10-2006	Kagimasa et al.	707/3
*	F	US-7,089,227	08-2006	Abe et al.	707/3
*	G	US-6,499,030	12-2002	lgata, Nobuyuki	707/6
*	Н	US-6,549,898	04-2003	Inaba et al.	707/5
*	١	US-6,665,667	12-2003	Inaba et al.	707/5
*	J	US-5,774,888	06-1998	Light, John	707/1
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	s					
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NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	υ							
	v							
	w							
	x							

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under